ON Semiconductor®

Final Product/Process Change Notification

Document #:FPCN23842X
Issue Date:08 Feb 2021

Title of Change:	Transfer of Assembly and Test site operations of Small Signal Junction Field Effect Transistor devices in TO-92 from AUKD (China) to JCET(China).
Proposed First Ship date:	17 May 2021 or earlier if approved by customer
Contact Information:	Contact your local ON Semiconductor Sales Office or Jason.Choy@onsemi.com
PCN Samples Contact:	Contact your local ON Semiconductor Sales Office or <PCN.samples@onsemi.com>. Sample requests are to be submitted no later than 30 days from the date of first notification, Initial PCN or Final PCN, for this change. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or Yasuhiro.Igarashi@onsemi.com
Type of Notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact PCN.Support@onsemi.com
Marking of Parts/ Traceability of Change:	Customer may receive the parts from JCET once FPCN expired or earlier depending on customer approval. Parts from new assembly & test site can be identified through product marking which follow ON Semiconductor marking format.
Change Category:	Test Change, Assembly Change
Change Sub-Category(s):	Manufacturing Site Transfer

Sites Affected:

ON Semiconductor Sites	**External Foundry/Subcon Sites**
None	AUK Corporation, Korea
	JCET, China

Description and Purpose:

This final notification announces the transfer of Assembly and Test Site on the Junction Field Effect Transistor packaged in TO-92 from AUKD (China) to JCET (China).

This change was resulted from AUKD (China) Assembly and Test site closure. The new site in JCET has been an existing qualified manufacturing site for ON Semiconductor which certified with IATF 16949:2016.

Products listed in this notification will continue to be Pb-free, Halide free and RoHS compliant. Qualification tests are designed to show that the reliability of the transferred devices will continue to meet or exceed ON Semiconductor standard.

Site Change:

	Before Change	After Change
Assembly Location	AUK, China	JCET, China
Final Test Location	AUK, China	JCET, China

TO92 Piece Part Change :

	Before Change	After Change
LeadFrame	CuAg STAMPED	No Change
Die Attach	Eutectic	No Change
Wire	Au wire	No Change
Mold Compound	Changchun EME 2500 D3	HHCK EMG-200

Reliability Data Summary:

QV DEVICE NAME : J109
PACKAGE : TO-92
RMS : S58670

Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Ta=150°C, 100 % max rated V	504 hrs	0/231
H3TRB	JESD22-A101	Ta=85°C, 85% / 80% max rated V	504 hrs	0/231
HTSL	JESD22-A103	Ta= 150°C	504 hrs	0/231
UHAST	JESD22-A118	Ta= 130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/231
TC	JESD22-A104	Ta= -55°C to 150°C	1000 cyc	0/231
IOL	MIL STD750 (M1037) AEC Q101	Ta=+25°C, deltaTj=100°C On/Off = 2 min	7500 cyc	0/231
PC	J-STD-020 JESD-A113	MSL 1 @ 260 °C		
RSH	JESD22- B106	Ta = 260C, 10 sec		0/30

Electrical Characteristics Summary:

Electrical characteristics are not impacted.

List of Affected Parts:

Note: *Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the* ***PCN Customized Portal.***

Part Number	Qualification Vehicle
J58	J109
J111-D26Z	J109
J111-D74Z	J109
J112-D26Z	J109
J112-D27Z	J109
J112-D74Z	J109
J113-D74Z	J109
J109-D26Z	J109

J176-D74Z	J109
J111	J109
J112	J109
J113	J109
J109	J109
J175-D26Z	J109
J211-D74Z	J109
BF256B	J109